Total No. of Questions: 8]	SEAT No.	:
P9599	[Total	No. of Pages :

## [6182] 973 M.E.(E & TC) (VLSL and Embedded Systems) ASIC DESIGN

(2017 Credit Pattern) (Semester - III) (604202)				
Time : 3	Hours] [Max. Marks	:50		
	ions to the candidates:			
1)	Attempt any 5 questions out of 8.			
2)	Neat diagrams must be drawn wherever necessary.			
3)	Figures to the right indicates full marks.			
4)	Assume suitable data, if necessary.			
<b>Q1</b> ) a)	Draw design flow of ASIC Design process and explain each step in de	etail.		
		[5]		
b)	What is test bench explain with one example.	[5]		
	8.			
<b>Q2</b> ) a)	What are different types of ASIC? Classify and explain in details.	<b>[5]</b>		
b)	Write VHDL code and test beach code for 8 bit counter.	[5]		
<b>Q3</b> ) a)	Differentiate floor-planning and placement in ASIC Design.	[4]		
b)	Write short note on gate level mixed mode testing.	[4]		
c)	List various CAD tools used in ASIC Design process.	[2]		
		5		
<b>Q4</b> ) a)	With neat labeled diagram explain clock distribution technique in ASIO	C.[ <b>4</b> ]		
b)	Compare global routing and detailed routing.	[4]		
c)	What is placement in ASIC Design? Write its goals and objectives.	[2]		
<b>Q5</b> ) a)	How false path detection is carried out in application specific intergr	ated		
	circuits.	[4]		
b)	What is the need of time optimization? Give one example which described	ibes		
,	time optimization in ASIC.	[4]		
c)	Differentiate pre layout simulation and post layout simulation technique	s.[ <b>2</b> ]		

<b>Q6</b> )	a)	What are different signal integrity issues? How it occurred in ASIC de	esign. [ <b>4</b> ]
	b)	What is functional simulation? Where it is required? Give one example	le.[ <b>4</b> ]
	c)	What are the time related constraints? Explain with one example.	[2]
<b>Q7</b> )	a)	Describe with one example static timing analysis.	[4]
	b)	Describe how memory testing is carried out in ASIC design.	[4]
	c)	What are different physical faults occurred in ASIC.	[2]
<b>Q</b> 8)	a)	Describe in brief Automatic Test Pattern Generator	[4]
	b)	Write short note on Joint Test Action Group.	[4]
	c)	Write types and features of existing EDA tools.	[2]
		Restricted to the second of th	

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